

Reliability Data Summary:			
QV DEVICE NAME:		DB-S	
Hi-real test	Sample size(PC)	Condition	ACC/REJ
High Temperature Reverse Bias	77	Ta=150°C±5°C VR=480V. for 1000 Hrs.	ACC
Thermal Fatigue Testing	77	ON: 300 sec / Off: 300 sec for 1000 cycles	ACC
Solder resistance	77	260±5°C for 10±2 Sec.	ACC
Thermal Shock	77	55°C±5°C/5MIN AND 150±5°C/5MIN for 100 cycles	ACC
Electrical Characteristic		Electrical characteris	stics are not impacted
List of Affected Parts:		Note: Only the standard (off the shelf) part numbers are this PCN are shown in the customer specific PCN addedustrated Portal.	endum in the PCN email notification, or on the PCN
Part Number	New spec version	Addition	Mark
DB101S DB102S DB103S DB104S DB105S DB106S DB107S	DB101S~DB107S 202004-97-E	Including to House #	
DB100S DB107S DB1012S	DB1012S-DB1014S 202004-97-B	Including to House #	
DB1014S	DB1012S-DB1014S 202004-97-B	Including to House #	
LDB101S-LDB107S	202004-97-B LDB101S ~ LDB107S 202004-97-B	Including to House #	
DB151S-DB1512S	DB151S~DB1512S 202004-97-D	Including to House #	
DB2014S	DB2014S 202004-97-B	Including to House #	
DB201S-DB207S	DB201S - DB207S 202004-97C	Including to House #	
EDB101S ~ EDB107S	EDB101S~EDB107S 202004-97-E	Including to House #	
KDB3200S	KDB3200S 202004-97-A	Including to House #	
DB159LS	DB159LS 202004-97-A	Including to House #	
HDB101IS-HDB108IS	HDB101LS~ HDB108LS 202004-97-A	Including to House #	
			V-AE19A1